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FEATURES

- All-silicon timing circuit
- Three independent buffered delays
- Stable and precise over temperature and voltage
- Leading and trailing edge precision preserves the input symmetry
- Standard 8-pin SO (150mil), and 8-Pin µSOP (118mil)
- Vapor phase and IR reflow solderable
- Available in Tape and Reel
- Delays specified over both commercial and . industrial temperature ranges
- 3V operation
- Recommended replacement for DS1033

DS1135L 3V 3-in-1 High-Speed Silicon Delay Line

PIN ASSIGNMENT

	_			
IN1	ш	1	8	Ⅲ v _{cc}
IN2	Щ	2	7	Ш ОUТ1
IN3	Щ	3	6	Π Ουτ2
GND	Щ	4	5	Ш ОИТЗ

DS1135LZ 8-Pin SO (150mil) DS1135LU 8-Pin µSOP (118mil) See Mech. Drawings Section

PIN DESCRIPTION

IN1-IN3	- Input Signals
OUT1-OUT3	- Output Signal
V _{CC}	- +3V Supply
GND	- Ground

Signals pply

DESCRIPTION

The DS1135L series is a low-power, 3V high-speed version of the popular DS1013, DS1033, DS1035 series.

The DS1135L series of delay lines have three independent logic buffered delays in a single package. The device is Dallas Semiconductor's fastest 3-in-1 delay line. It is available in a standard 8-pin 118mil µSOP and 150mil 8-pin Mini-SO.

The device features precise leading and trailing edge accuracy. It has the inherent reliability of an allsilicon delay line solution.

Standard delay values are indicated in Table 1. Customers may contact Dallas Semiconductor at (972) 371-4348 for further information on custom delay values.

LOGIC DIAGRAM Figure 1



ONE OF THREE

PART NUMBER DELAY TABLE (t_{PLH}, t_{PHL}) Table 1

	DELAY PER OUTPUT	INITIAL TOLERANCE	TOLERANCE OVER TEMP AND VOLTAGE (Note 2)		
PART NUMBER	(ns)	(Note 1)	0°C to +70°C -40°C to +85°		
DS1135LX-10	10/10/10	±1.0ns	±2.0ns	±3.0ns	
DS1135LX-12	12/12/12	±1.0ns	±2.0ns	±3.0ns	
DS1135LX-15	15/15/15	±1.0ns	±2.5ns	±4.0ns	
DS1135LX-20	20/20/20	±1.0ns	±2.5ns	±4.0ns	
DS1135LX-25	25/25/25	±1.5ns	±3.0ns	±5.0ns	
DS1135LX-30	30/30/30	±1.5ns	±3.0ns	±5.0ns	

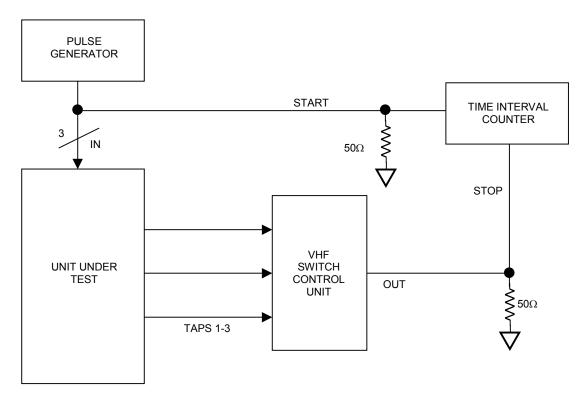
NOTES:

- 1. Nominal conditions are +25°C and V_{CC} = +3.3V.
- 2. Voltage range of 2.7V to 3.6V.
- 3. Delay accuracies is for both leading and trailing edges.
- 4. X in Part number denotes package: U indicates µSOP, Z indicates SO.

TEST SETUP DESCRIPTION

Figure 2 illustrates the hardware configuration used for measuring the timing parameters of the DS1135L. The input waveform is produced by a precision pulse generator under software control. Time delays are measured by a time interval counter (20 ps resolution) connected to the output. The DS1135L output taps are selected and connected to the interval counter by a VHF switch control unit. All measurements are fully automated with each instrument controlled by the computer over an IEEE 488 bus.

DS1135L TEST CIRCUIT Figure 2



ABSOLUTE MAXIMUM RATINGS*

Voltage on Any Pin Relative to Ground Operating Temperature Storage Temperature Soldering Temperature Short Circuit Output Current

-1.0V to +6.0 V -40°C to +85°C -55°C to +125°C See J-STD-020A specification 50mA for 1 second

* This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operation sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods of time may affect reliability.

DC ELECTRICAL CH	(-40°C to +85°C;V _{CC} =2.7-3.6V)					
PARAMETER	SYMBOL	TEST CONDITION	MIN	ТҮР	MAX	UNITS
Supply Voltage	V _{CC}		2.7	3.3	3.6	V
Active Current	I _{CC}	V _{CC} =3.6V Period=1µs			10	mA
High Level Input Voltage	V _{IH}		2.0		V _{CC} +0.5	V
Low Level Input Voltage	V _{IL}		-0.5		0.8	V
Input Leakage	IL	$0V \leq V_I \leq V_{CC}$	-1.0		+1.0	μΑ
High Level Output Current	I _{CC}	V _{CC} =2.7V V _{OH} =2V			-1.0	mA
Low Level Output Current	I _{CC}	V _{CC} =2.7V V _{OL} =0.4V	8			mA

AC ELECTRICAL CHARACTERISTICS

(-40°C to +85°C;V_{CC}=2.7-3.6V)

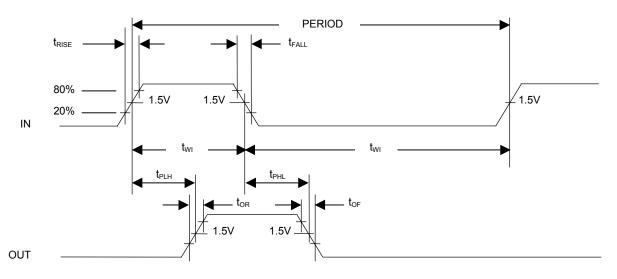
PARAMETER	SYMBOL	MIN	ТҮР	MAX	UNITS	NOTES
Period	t _{PERIOD}	$2(t_{WI})$			ns	
Input Pulse Width	$t_{\rm WI}$	100% of Delay Value			ns	
Input-to-Output Delay	$t_{\rm PLH}, t_{\rm PHL}$	See Table 1		ns		
Output Rise or Fall Time	t _{OF} , t _{OR}		2.0	2.5	ns	
Power-up Time	t _{PU}			1	ms	2

CAPACITANCE (T _A =25°							
PARAMETER	SYMBOL	MIN	ТҮР	MAX	UNITS	NOTES	
Input Capacitance	C _{IN}			10	pF		

TEST CONDITIONS

Note: The above conditions are for test only and do not restrict the devices under other data sheet conditions.

TIMING DIAGRAM



NOTES:

- 1. All voltages are referenced to ground.
- 2. Power-up time is the time from the application of power to the time stable delays are being produced at the output.

TERMINOLOGY

Period: The time elapsed between the leading edge of the first pulse and the leading edge of the following pulse.

 t_{WI} (Pulse Width): The elapsed time on the pulse between the 1.5V point on the leading edge and the 1.5V point on the trailing edge or the 1.5V point on the trailing edge and the 1.5V point on the leading edge.

 t_{RISE} (Input Rise Time): The elapsed time between the 20% and the 80% point on the leading edge of the input pulse.

 t_{FALL} (Input Fall Time): The elapsed time between the 80% and the 20% point on the trailing edge on the input pulse.

 t_{PLH} (Time Delay, Rising): The elapsed time between the 1.5V point on the leading edge of the input pulse and the 1.5V point on the leading edge of the output pulse.

 t_{PHL} (Time Delay, Falling): The elapsed time between the 1.5V point on the falling edge of the input pulse and the 1.5V point on the falling edge of the output pulse.

ORDERING INFORMATION

